



Date Created: 2/16/2004
Date Issued: 3/3/2004
PCN # 20040703

FORECAST CHANGE NOTIFICATION

This is to inform you that a design and/or process change will be made to the following product(s). This notification is for your information and concurrence. This is a preliminary notification. A final PCN will be issued when qualification is complete and data is available.

If you require data or samples to qualify this change, please contact **Fairchild Semiconductor within 30 days of receipt of this notification.**

If you have any questions concerning this change, please contact:

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PCN Originator

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PCN Type: Alternate Fab Location

Effectivity

Expected 1st Device Shipment Date: 6/14/2004
Earliest Year/Work Week of Changed Product: 0425
(Note: Package marking may differ from this format)

Product ID (Description):

Standard Schottky Diode 30V/0.2A, SOT-23, BAT54/A/C/S.BAR43/A/C/S.

Description of Change:

The chip of standard schottky diode BAT54/A/C/S,BAR43/A/C/S and their stampoff products is provided by Torex in Japan.
The chip of BAT54/A/C/S and BAR43/A/C/S will be replaced by the chip from Fairchild In-House Fab. line which locate in Bucheon Korea .
The new chip will have a same chip size, same characteristics and same quality of old KA die.

Effect of Change:

There will be no impact to the electrical characteristics of these products.
This change will enlarge the production capacity to meet any customer's need.

Qualification:

The qualification plan is intended to meet all our criteria for qualifying an alternate fabrication site and the overall quality and reliability of our products.

Qual/REL Plan Numbers

Additional Qualification Data

Test#	Test Description	Conditions	Duration
1	High Temperature(HTRB)	150Deg C, Vr@80% =24V	1000HR
2	Temperature Humidity Bias Test(THBT)	85%RH, 85 Deg C, Vr=10V	1000HR
3	Direct Current Operating Life(DCOL)	25Deg C '@Rated Pd, R=10ohms	168HR
4	Autoclave(ACLV)	121Deg C, 100% RH	96HR
5	Temperature Cycle(TMCL)	-65 to +150Deg C,15mins Dwell	500CYCLE
6	Others/Special instructions	Pre-con Required	

Device	Test	Rel. No	HTRB	THBT	TMCL	DCOL	ACLV
BAT54A SOT-23	F9Z17#2	230216	77ea	77ea	77ea	77ea	77ea
	F9Z18#3	230217	77ea	77ea	77ea	77ea	77ea
	F9Z19#4	230218	77ea	77ea	77ea	77ea	77ea

Affected FSIDs

BAR43
BAR43S
BAT54C

BAR43A
BAT54
BAT54S

BAR43C
BAT54A
KA49